SLOVENSKI STANDARD

SIST EN 61988-2-1:2005

december 2005

Prikazalniki s plazmo – 2-1. del: Merilne metode – Optične (IEC 61988-2-1:2002)

Plasma display panels – Part 2-1: Measuring methods – Optical (IEC 61988-2-1:2002)

iTeh STANDARD PREVIEW (standards.iteh.ai)

SIST EN 61988-2-1:2005 https://standards.iteh.ai/catalog/standards/sist/bee0bbec-5040-4141-9c81-32534ef285e7/sist-en-61988-2-1-2005

ICS 31.120

Referenčna številka SIST EN 61988-2-1:2005(en)

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<u>SIST EN 61988-2-1:2005</u> https://standards.iteh.ai/catalog/standards/sist/bee0bbec-5040-4141-9c81-32534ef285e7/sist-en-61988-2-1-2005

EUROPEAN STANDARD

EN 61988-2-1

NORME EUROPÉENNE

EUROPÄISCHE NORM

December 2002

ICS 31.260

English version

Plasma display panels Part 2-1: Measuring methods - Optical

(IEC 61988-2-1:2002)

Panneaux d'affichage à plasma Partie 2-1: Méthodes de mesure -Optiques (CEI 61988-2-1:2002) Plasmabildschirme Teil 2-1: Messverfahren -Optisch (IEC 61988-2-1:2002)

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This European Standard was approved by CENELEC on 2002-11-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration 5040-4141-9c81-

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Luxembourg, Malta, Netherlands, Norway, Portugal, Slovakia, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 47C/276/FDIS, future edition 1 of IEC 61988-2-1, prepared by SC 47C, Flat panel display devices, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61988-2-1 on 2002-11-01.

The following dates were fixed:

 latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement

(dop) 2003-08-01

 latest date by which the national standards conflicting with the EN have to be withdrawn

(dow) 2005-11-01

Annexes designated "normative" are part of the body of the standard. In this standard, annex ZA is normative.

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 61988-2-1:2002 was approved by CENELEC as a European Standard without any modification.

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SIST EN 61988-2-1:2005 https://standards.iteh.ai/catalog/standards/sist/bee0bbec-5040-4141-9c81-32534ef285e7/sist-en-61988-2-1-2005

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 61988-1	_ 1)	Plasma display panels Part 1: Terminology and letter symbols	EN 61988-1	_ 1)
IEC 60068-1	- 2)	Environmental testing Part 1: General and guidance	EN 60068-1	1994 ³⁾
IEC 60107-1	- ²⁾ iT	Methods of measurement on receivers for television broadcast transmissions Part (: General considerations - 21) Measurements at radio and video frequencies	EN/60107-1	1997 ³⁾
CIE 15.2	https://sta	undards iteh ai/catalog/standards/sist/bee0bbec-5040-4 Colorimetry 32534ef285e7/sist-en-61988-2-1-2005	1 <u>4</u> 1-9c81-	-

²⁾ Undated reference.

¹⁾ At draft stage.

³⁾ Valid edition at date of issue.

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NORME INTERNATIONALE INTERNATIONAL **STANDARD**

CEI **IEC** 61988-2-1

> Première édition First edition 2002-10

Panneaux d'affichage à plasma -

Partie 2-1: Méthodes de mesure – Optiques

Plasma display panels – (standards.iteh.ai)
Part 2-1:

Measuring methods - Optical

https://standards.iteh.ai/catalog/standards/sist/bee0bbec 32534ef285e7/sist-en-61988-2-1-2005

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CODE PRIX PRICE CODE

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

PLASMA DISPLAY PANELS -

Part 2-1: Measuring methods - Optical

FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61988-2-1 has been prepared by subcommittee 47C: Flat panel display devices, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47C/276/FDIS	47C/280/RVD

Full information on the voting for the approval on this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

IEC 61988 will consist of the following parts, under the general title Plasma display panels:

Part 1: Terminology and letter symbols:

Part 2-1: Measuring methods – Optical;

Part 2-2: Measuring methods – Optoelectrical;

Part 3: Guidelines of mechanical interface;

Part 4: Environmental, endurance and mechanical test methods.